**Defect Life cycle**



Defect life cycle describes a process to manage defects or defects with different status.

Firstly, the tester performs a function test and found out a defect, he reports a new defect on a program which used to manage defect life cycle (such as: TFS or something like that). He creates a status which is new for this defect.

Secondly, if the developer – who take charge this function that was tested and find out the defect – suppose that the defect has already been reported, he will change defect’s status into Rejected and describes briefly a defect is “duplicated” and the tester reconfirm it and change the status into closed. Else the defect is supposed that not to report and go to the next step.

Thirdly, the developer keeps check if it is a real defect. If it is true, the developer will change the status into open. If it isn’t, the developer will change the status into Rejected and describes briefly a defect is “not defect” and the test reconfirm it and change the status into closed.

Fourthly, the defect is assigned for a developer to fix.

* If the developer suppose that the defect can’t be reproduced and need more info, he will change into pending and the test will check the defect, give more defect information (for example, how is the defect occurred? listed step by step), update the defect report and change the status into reopen. After then, the defect will re-assign for the developer who fix this defect.
* Else if the defect can be reproduced, the developer is going to fix the defect right now. If the defect is too hard to resolve and need further analysis, the developer will change the status into further analysis. Else if the defect can fix, the developer is going to resolve the defect and changes the status into resolved.

Fifthly, the tester reviews this solved-defect and change the status into tested. If the tester supposes that the defect isn’t fixed yet, the tester will change the status into reopen; else if the defect is fixed successful, the status change into approved and the tester close the defect.